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 Day : Sunday
 Date: 3/4/2007
 Time: 15:23:38
Inventor Name Search Result

Your Search was:

Last Name = KURITA

First Name = KAZUNARI

Application#	Patent#	Status	Date Filed	Title	Inventor Name
*10531434	Not Issued	30	02/17/2006	Method for measuring point defect distribution of silicon single crystal ingot	KURITA, KAZUNARI
10576321	Not Issued	25	04/19/2006	Process for producing high-resistance silicon wafers and process for producing epitaxial wafers and soi wafers (as amended)	KURITA, KAZUNARI
*10784411	7074271	150	02/23/2004	METHOD OF IDENTIFYING DEFECT DISTRIBUTION IN SILICON SINGLE CRYSTAL INGOT	KURITA, KAZUNARI
11700492	Not Issued	19	01/01/0001	High frequency diode and method for producing same	KURITA, KAZUNARI

Inventor Search Completed: No Records to Display.

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<input type="text" value="Kurita"/>	<input type="text" value="Kazunari"/>
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PALM INTRANET

 Day : Sunday
 Date: 3/4/2007
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Inventor Name Search Result

Your Search was:

Last Name = FURUKAWA

First Name = JUN

Application#	Patent#	Status	Date Filed	Title	Inventor Name
06659755	Not Issued	161	10/11/1984	ANTITUMOR AGENT AND METHOD FOR TREATING TUMOR USING THE SAME	FURUKAWA, JUN
07559628	Not Issued	166	07/30/1990	HIGH-STRENGTH, DAMAGE-RESISTANT RAIL	FURUKAWA, JUN
07774819	Not Issued	166	10/11/1991	ROLLING ROLLER AND ROLLING MILL	FURUKAWA, JUN
07866129	5209792	150	04/07/1992	HIGH-STRENGTH, DAMAGE-RESISTANT RAIL	FURUKAWA, JUN
07873602	5166964	150	04/21/1992	METHOD AND APPARATUS FOR MEASURING DENSITY	FURUKAWA, JUN
07932564	5242766	150	08/20/1992	HYDROGEN-OCLUSION ELECTRODE	FURUKAWA, JUN
07932568	Not Issued	166	08/20/1992	METHOD OF MANUFACTURING A SEALED-TYPE NICKEL-HYDROGEN CELL	FURUKAWA, JUN
07970656	5327762	150	11/02/1992	ROLLING ROLLER AND ROLLING MILL	FURUKAWA, JUN
08046846	Not Issued	164	04/14/1993	SEALED-TYPE NICKEL/HYDROGEN ALKALINE STORAGE BATTERY	FURUKAWA, JUN
08064866	5322527	250	05/24/1993	METHOD OF MANUFACTURING SEALED-TYPE STORAGE BATTERIES USING HYDROGEN-OCLUSION ELECTRODES	FURUKAWA, JUN
08095257	5395712	150	07/22/1993	PASTE-TYPE NICKEL ELECTRODE FOR AN ALKALINE STORAGE BATTERY AND AN ALKALINE STORAGE BATTERY CONTAINING THE	FURUKAWA, JUN

				ELECTRODE	
08138382	5334226	250	10/20/1993	METHOD OF MANUFACTURING A SEALED-TYPE NICKEL-HYDROGEN CELL	FURUKAWA, JUN
08162773	5435055	250	12/08/1993	METHOD OF MANUFACTURING A SEALED ALKALINE STORAGE BATTERY USING POSITIVE PASTE NICKEL ELECTRODES	FURUKAWA, JUN
08173075	5441833	150	12/27/1993	PASTE NICKEL ELECTRODE PLATE AND A STORAGE BATTERY INCLUDING AN ELECTROCONDUCTIVE MATERIAL	FURUKAWA, JUN
08200464	Not Issued	161	02/23/1994	SEALED-TYPE NICKEL/HYDROGEN ALKALINE STORAGE BATTERY	FURUKAWA, JUN
08215476	5384210	250	03/21/1994	HYDROGEN-OCCULSION ALLOY FOR THE ELECTRODES OF A SEALED-TYPE STORAGE BATTERY	FURUKAWA, JUN
08217943	5466544	150	03/25/1994	METHOD FOR MANUFACTURING A HYDROGEN-OCCLUSION-ALLOY ELECTRODE	FURUKAWA, JUN
08293847	5496665	150	08/22/1994	HYDROGEN-OCCLUSION-ALLOY ELECTRODE	FURUKAWA, JUN
08314328	5542958	150	09/28/1994	METHOD FOR MANUFACTURING A HYDROGEN ABSORBING ALLOY ELECTRODE	FURUKAWA, JUN
08444862	5514497	150	05/19/1995	PASTE NICKEL ELECTRODE PLATE AND A STORAGE BATTERY INCLUDING AN ELECTROCONDUCTIVE MATERIAL	FURUKAWA, JUN
08709722	5775602	250	09/09/1996	MANUFACTURING METHOD FOR A HYDROGEN-STORAGE-ALLOY POWDER FOR BATTERIES	FURUKAWA, JUN
08785647	Not Issued	161	01/17/1997	HIGH-STRENGTH, DAMAGE-RESISTANT RAIL HAVING HARDNESS DISTRUBUTION OF EXCELLENT DAMAGE-	FURUKAWA, JUN

				RESISTANCE AT ITS HEAD TOP PORTION	
08863220	5876874	250	05/27/1997	NICKEL ELECTRODE FOR SECONDARY BATTERY	FURUKAWA, JUN
09231440	6361625	250	01/14/1999	HIGH-STRENGTH, DAMAGE- RESISTANT RAIL HAVING HARDNESS DISTRIBUTION OF EXCELLENT DAMAGE- RESISTANCE AT ITS HEAD TOP PORTION	FURUKAWA, JUN
09397202	6804827	150	09/16/1999	TRANSMISSION SYSTEM AND METHOD SIGNAL ADJUSTING APPARATUS AND METHOD AND ROUTING APPARATUS	FURUKAWA, JUN
09667885	6663708	150	09/22/2000	SILICON WAFER, AND MANUFACTURING METHOD AND HEAT TREATMENT METHOD OF THE SAME	FURUKAWA, JUN
09718659	Not Issued	161	11/22/2000	Silicon wafer and method for manufacturing the same	FURUKAWA, JUN
09796458	7035404	150	03/02/2001	METHOD AND APPARATUS FOR SHUFFLE WITH PROOF, METHOD AND APPARATUS FOR SHUFFLE VERIFICATION, METHOD AND APPARATUS FOR GENERATING INPUT MESSAGE SEQUENCE AND PROGRAM FOR SAME	FURUKAWA, JUN
09806550	6447600	150	03/30/2001	DEFECT ELIMINATING METHOD OF SINGLE CRYSTAL BODY, AND SINGLE CRYSTAL BODY DEFECT- ELIMINATED BY SUCH METHOD	FURUKAWA, JUN
09875146	6558483	150	06/07/2001	CU PRECIPITATION STRENGTHENED STEEL	FURUKAWA, JUN
10137407	Not Issued	93	05/03/2002	CERTIFIED SHUFFLE- DECRYPTING SYSTEM, CERTIFIED SHUFFLE- DECRYPTING METHOD AND CERTIFIED SHUFFLE- DECRIPTION VERIFYING METHOD	FURUKAWA, JUN
10164311	7039825	150	06/07/2002	CLOCK REPRODUCING METHOD AND RECEIVING CLOCK PRODUCING APPARATUS ALLOWING FOR	FURUKAWA, JUN

				ABSORBTION OF TRANSMISSION CHANNEL JITTER	
10212172	7003541	150	08/06/2002	ZERO-KNOWLEDGE PROVING SYSTEM AND METHOD	FURUKAWA, JUN
10521035	Not Issued	95	08/02/2005	METHOD FOR MANUFACTURING SILICON SINGLE CRYSTAL	FURUKAWA, JUN
*10531434	Not Issued <i>Applicant's Invention</i>	30	02/17/2006	Method for measuring point defect distribution of silicon single crystal ingot	FURUKAWA, JUN
10546645	Not Issued	20	08/24/2005	Mixnet system	FURUKAWA, JUN
10558790	Not Issued	20	11/28/2005	Method of simulation with respect to density distribution and size distribution of void defect within single crystal and oxygen precipitation nucleus within single crystal	FURUKAWA, JUN
10587308	Not Issued	19	01/01/0001	Method and device for calculating a function from a large number of inputs	FURUKAWA, JUN
10628690	Not Issued	161	07/28/2003	Method of manufacturing silicon	FURUKAWA, JUN
10718663	Not Issued	25	11/24/2003	Weakly computational zero- knowledge proof and evaluation	FURUKAWA, JUN
10754111	Not Issued	71	01/08/2004	Lead-based alloy for lead-acid battery, substrate for lead-acid battery and lead-acid battery	FURUKAWA, JUN
*10784411	7074271 <i>Review application of Bob Kinnane</i>	150	02/23/2004	METHOD OF IDENTIFYING DEFECT DISTRIBUTION IN SILICON SINGLE CRYSTAL INGOT	FURUKAWA, JUN
10951807	Not Issued	30	09/29/2004	Pulse based communication system	FURUKAWA, JUN
10995478	Not Issued	30	11/24/2004	Cryptographic communication system	FURUKAWA, JUN
11030488	Not Issued	61	01/05/2005	Lead-based alloy for lead-acid battery, grid for lead-acid battery and lead-acid battery	FURUKAWA, JUN
11130228	Not Issued	30	05/17/2005	Impulse-based communication system	FURUKAWA, JUN
11382121	Not Issued	25	05/08/2006	Method For Manufacturing Nitrogen-Doped Silicon Single Crystal	FURUKAWA, JUN

<u>11553854</u>	Not Issued	25	10/27/2006	Method for manufacturing silicon single crystal	FURUKAWA, JUN
<u>06420843</u>	4475492	250	09/21/1982	SYSTEM FOR FORCEFULLY IGNITING SPRAYED FUEL OF A DIESEL ENGINE DURING ENGINE STARTING	FURUKAWA, JUNICHI
<u>06442906</u>	4457285	250	11/19/1982	SUSTAINED ARC IGNITION SYSTEM FOR AN INTERNAL COMBUSTION ENGINE	FURUKAWA, JUNICHI

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10/531434

Examiner: HITESHEW, FELISA

GAU: 1722

Classification: 117/013.000

Inventor: KURITA, KAZUNARI, et al
Status: 30 - DOCKETED NEW CASE - READY FOR EXAMINATION
Title: METHOD FOR MEASURING POINT DEFECT DISTRIBUTION OF SILICON SINGLE CRYSTAL INGOT

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IDS	Doc Code	Date	Pages	Annot Avail	Content	Entry #	Review Date	Reviewer
X	IDS	04/15/2005	3				N/A	

10/531434

Inventor: KURITA, KAZUNARI, et al

Status: 30 - DOCKETED NEW CASE - READY FOR EXAMINATION

Title: METHOD FOR MEASURING POINT DEFECT DISTRIBUTION OF SILICON SINGLE CRYSTAL INGOT

Examiner: HITESHEW, FELISA

GAU: 1722
Classification: 117/013.000

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	7	NPL	NPL Documents	04/15/2005	1	
	7	NPL	NPL Documents	04/15/2005	2	
	13	FOR	Foreign Reference	04/15/2005	38	
	13	FOR	Foreign Reference	04/15/2005	14	